DTIP Panel 2006: Design for Reliability and Test of Microsystems

Patric Salomon, 4M2C

May-06

«Design for Micro & Nano Manufacture (NoE PATENT-DfMM)»
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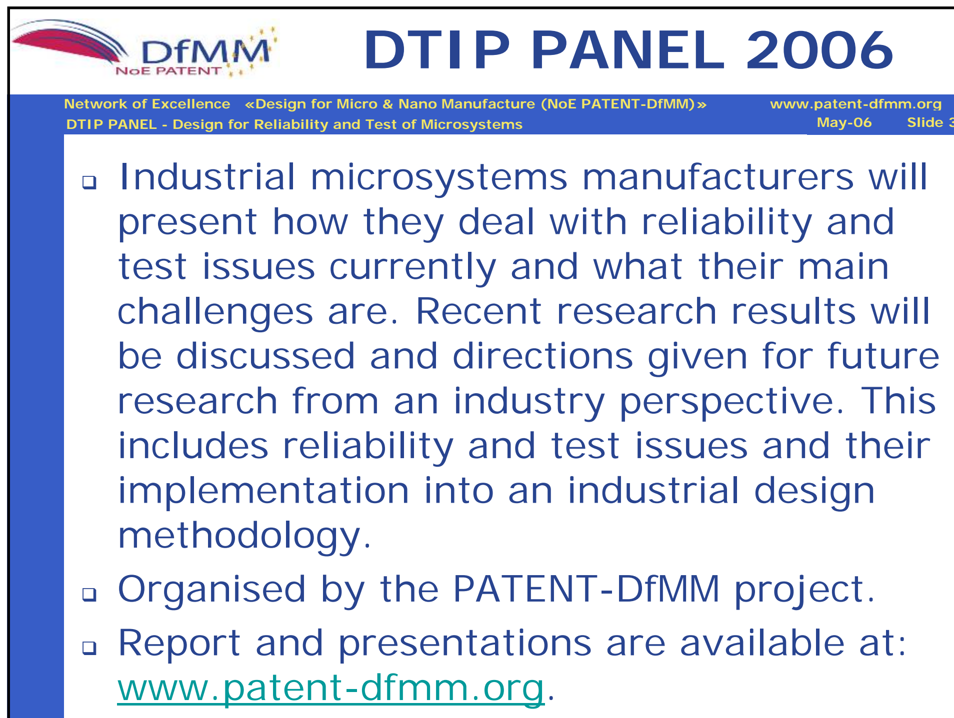
DTIP PANEL - Design for Reliability and Test of Microsystems May-06 Slide 2

Panel: Design for Reliability and Test of Microsystems

- Ludo Stulens, Philips
- Augustin Coello-Vera, Alcatel Space
- Xavier Lafontan, NOVA MEMS
- Andrew Richardson, Lancaster University

Moderation: Patric Salomon, 4M2C PATRIC SALOMON GmbH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Slide 3
Industrial microsystems manufacturers will present how they deal with reliability and test issues currently and what their main challenges are. Recent research results will be discussed and directions given for future research from an industry perspective. This includes reliability and test issues and their implementation into an industrial design methodology.
Organised by the PATENT-DfMM project.
Report and presentations are available at: www.patent-dfmm.org.